

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 257558US0PCT		SERIAL NO. 10/505,450	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Gunther PABST, et al.			
				FILING DATE September 1, 2004		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/SRH/	AA	6 157 730	12/05/00	Wei WEN et al.			
	AB						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/SRH/	AC	42 16 469	11/25/93	DE(English abstract only)			NO
/SRH/	AD	198 24 304	12/02/99	DE(English abstract only)			NO
/SRH/	AE	44 26 783	02/09/95	DE(English abstract only)			NO
/SRH/	AF	704 469	04/03/96	EP(equivalent of CA 2159265)			NO
/SRH/	AG	42 30 068	03/10/94	DE(English abstract only)			NO
	AI	42 34 323	04/13/94	DE(English abstract only)			NO
	AI	197 37 703	03/04/99	DE(English abstract only)			NO
	AJ	02/00268	08/11/97	WO			NO
/SRH/	AK	1 107 377	06/13/01	EP(equivalent of US 6332815)			NO
	AL	198 22 224	11/25/99	DE(English abstract only)			NO
	AM	39 28 095	02/28/91	DE(English abstract only)			NO
	AN	279 303	08/24/88	EP(equivalent of US 5096938)			NO
	AO	012 339	06/25/80	EP(equivalent of US 4287039)			NO
	AP	1672216	08/23/91	SU(English abstract only)			NO
	AQ	92/08811	05/29/92	WO(equivalent of CA 2095934)			NO
	AR	3-071047	03/26/91	JP(English abstract only)			NO
	AS	329 488	08/23/89	EP			NO
	AT	2100439	12/27/97	RU(English abstract only)			NO
	AU	2124561	01/10/99	RU(English abstract only)			NO
/SRH/	AV	26 20 229	03/10/89	FR(English abstract only)			NO
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/SRH/	AW	Erik KLAAS, "Measurement of grain structures using 3D scanning", WORLD LEATHER, issue 9, page 44 2001					
	AX						
	AY						
	AZ						
Examiner /Shaun Hurley/					<input type="checkbox"/> Additional References sheet(s) attached Date Considered 04/14/2008		

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.